NOV 2.3. 2005 gg.

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

- 1. (Currently Amended) An image sensor comprising:
- (a) a semi-conducting substrate having a photo-sensitive region and doping for forming a path to a charge-to-voltage mechanism;
 - (b) a dielectric spanning the substrate; and
- (c) a <u>single crystal</u> semi-conducting layer, which is less than approximately 1 micrometer, spanning the dielectric which contains electrodes and circuit elements that control flow of charge.
- 2. (Original) The image sensor as in claim 1, wherein the semiconducting substrate and semi-conducting layer are silicon.
- 3. (Original) The image sensor as in claim 2, wherein the dielectric is silicon dioxide.
- 4. (Original) The image sensor as in claim 3, wherein the semiconducting substrate includes an epitaxial layer.
- 5. (Original) The image sensor as in claim 1 further comprising doping for a reset transistor in the semi-conducting substrate and a reset gate in the semi-conducting layer.
- 6. (Original) The image sensor as a claim 1, wherein the photosensitive region is a photodiode.
- 7. (Original) The image sensor as in claim 1, wherein the charge-to-voltage mechanism is a floating diffusion.
- 8. (Original) The image sensor as in claim 1, wherein the image sensor is a CMOS image sensor.

9-11. (Canceled)

- 12. (Currently Amended) A camera comprising: an image sensor comprising:
- (a) a semi-conducting substrate having a photo-sensitive region and doping for forming a path to a charge-to-voltage mechanism;
 - (b) a dielectric spanning the substrate; and
- (c) a <u>single crystal</u> semi-conducting layer, which is less than approximately 1 micrometer, spanning the dielectric which contains electrodes and circuit elements that control flow of charge.
- 13. (Original) The camera as in claim 12, wherein the semi-conducting substrate and semi-conducting layer are silicon.
- 14. (Original) The camera as in claim 13, wherein the dielectric is silicon dioxide.
- 15. (Original) The camera as in claim 14, wherein the semiconducting substrate includes an epitaxial layer.
- 16. (Original) The camera as in claim 12 further comprising doping for a reset transistor in the semi-conducting substrate and a reset gate in the semi-conducting layer.
- 17. (Original) The camera as in claim 12, wherein the photosensitive region is a photodiode.
- 18. (Original) The camera as in claim 12, wherein the charge-to-voltage mechanism is a floating diffusion.
- 19. (Original) The camera as in claim 12, wherein the image sensor is a CMOS image sensor.

Amendments to the Drawings:

Formal drawings are submitted herewith under Separate Letter to the Draftsperson. For the convenience of the Examiner, a copy of the formal drawings are also attached with this amendment.

Attachment: Replacement Figures 1-3